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**Study of fabrication of InSb thin films on GaAs substrate
in potential application for IoT**

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Indium antimonide (InSb) has been extensively investigated for many years, renowned for its low energy gap of approximately 0.18 eV at room temperature, along with its outstanding mobility of electric charge carriers, recorded at 77000 cm²/(V·s) [1]. The advancement of device fabrication techniques creates new opportunities for thin layers of InSb. Implementing the lithography process followed by metal deposition in vacuum conditions onto the graphene layer enables the creation of complex planar structures with distinctive functionality [2]. A minor adjustment to this structuring method makes it feasible to adapt the technology to thicker layers, such as InSb.

High-quality InSb thin films are produced using the Flash Evaporation Method (FEM) under high vacuum conditions on a gallium arsenide (GaAs) substrate. After a modified structuring approach, Hall and TLM structures were created to assess the galvanometric properties of the InSb-based hybrid structures. Furthermore, a structure was proposed to evaluate the effectiveness of the strip magneto sensor (SMS) in the InSb material [3]. Due to the high mobility of the charge carriers in InSb, it is expected that a notable magnetoresistive effect will be observed in specific geometric configurations, which enhances the potential for developing a magnetoresistive sensor that could be an integral component of the Internet of Things (IoT) [4].

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